

Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/540,391	TAKAHASHI ET AL.	
Examiner	Art Unit	
Thai Phan	2129	

SEARCHED				
Class	Subclass	Date	Examiner	
703	2	11/14/2008	T.P.	
703	27	11/14/2008	T.P.	
716	1, 8	11/14/2008	T.P.	
715	764	11/14/2008	T.P.	
707	3	11/14/2008	T.P.	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
703	2	11/14/2008	T.P.	
703	27	11/14/2008	T.P.	
716	1, 8	11/14/2008	T.P.	
715/764 707/3		11/14/2008	T.P.	

SEARCH (INCLUDING SEAR		·)
	DATE	EXMR
US patent search	11/1842008	T.P.
npl search	11/14/2008	T.P.
update search	11/14/2008	T.P.